

### **AMENDMENTS TO THE SPECIFICATION**

Please add a new section and new section heading immediately after the title as follows:

#### **CROSS-REFERENCE TO RELATED APPLICATIONS**

This is a U.S. National Stage application of PCT/GB2003/002875, filed 4 July 2003, the entirety of which is incorporated herein by reference. This application also claims the benefit of British patent application no. 0215736.0, filed 6 July 2002.

#### **BACKGROUND**

Please insert a heading and amend the paragraphs at page 5, lines 11-22 as follows:

#### **SUMMARY**

~~It is an object of~~ One aspect of the invention ~~to can~~ mitigate some or all of these disadvantages and so improve accuracy and reproducibility of ECV profile measurements.

~~It is a particular object~~ Another aspect of the invention ~~to provide~~ provides a method of ECV profiling which allows for viewing of the sample during electrolyte filling and ECV profiling and for viewing and measuring the etched well area, without the need to remove the sample from the apparatus.

~~It is a particular object~~ aspect of the invention, ~~to provide~~ a method of ECV profiling ~~which provides~~ valuable information to the user to optimize the conditions, to alleviate problems with gas bubbles and surface films and to improve the accuracy and repeatability of the measurement.

Please insert the following heading as a separate line before the paragraph at page 11, lines 6 and 7:

**BRIEF DESCRIPTION OF THE DRAWINGS**

Please insert the following heading as a separate line before the paragraph at page 11, lines 20 and 21:

**DETAILED DESCRIPTION**